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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	80
Number of Logic Elements/Cells	640
Total RAM Bits	18432
Number of I/O	78
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-640hc-4tg100c

The logic blocks, Programmable Functional Unit (PFU) and sysMEM EBR blocks, are arranged in a two-dimensional grid with rows and columns. Each row has either the logic blocks or the EBR blocks. The PIO cells are located at the periphery of the device, arranged in banks. The PFU contains the building blocks for logic, arithmetic, RAM, ROM, and register functions. The PIOs utilize a flexible I/O buffer referred to as a sysIO buffer that supports operation with a variety of interface standards. The blocks are connected with many vertical and horizontal routing channel resources. The place and route software tool automatically allocates these routing resources.

In the MachXO2 family, the number of sysIO banks varies by device. There are different types of I/O buffers on the different banks. Refer to the details in later sections of this document. The sysMEM EBRs are large, dedicated fast memory blocks; these blocks are found in MachXO2-640/U and larger devices. These blocks can be configured as RAM, ROM or FIFO. FIFO support includes dedicated FIFO pointer and flag “hard” control logic to minimize LUT usage.

The MachXO2 registers in PFU and sysI/O can be configured to be SET or RESET. After power up and device is configured, the device enters into user mode with these registers SET/RESET according to the configuration setting, allowing device entering to a known state for predictable system function.

The MachXO2 architecture also provides up to two sysCLOCK Phase Locked Loop (PLL) blocks on MachXO2-640U, MachXO2-1200/U and larger devices. These blocks are located at the ends of the on-chip Flash block. The PLLs have multiply, divide, and phase shifting capabilities that are used to manage the frequency and phase relationships of the clocks.

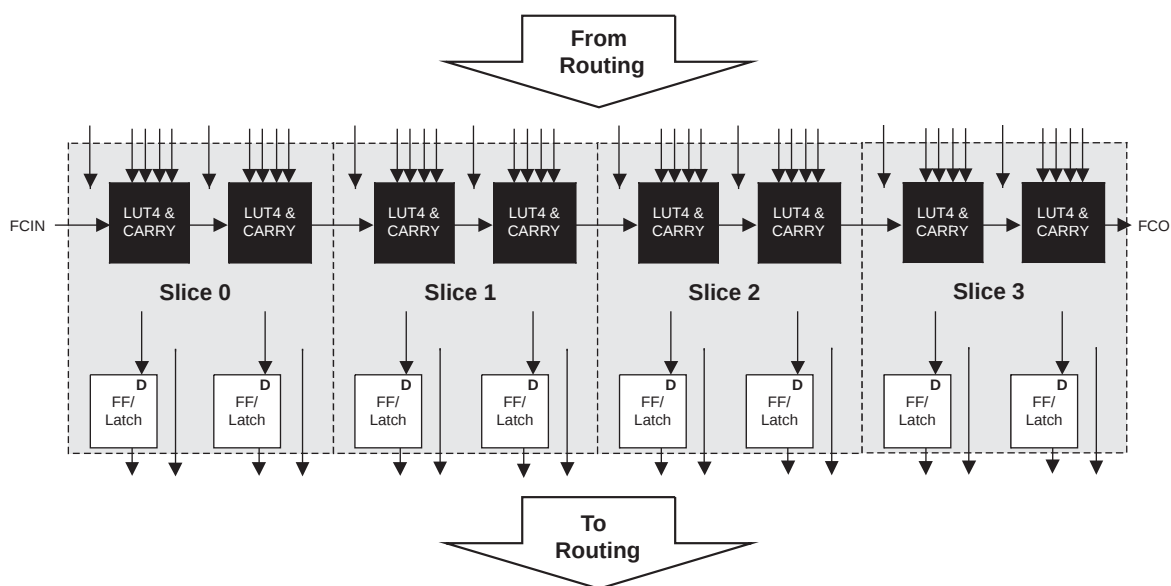
MachXO2 devices provide commonly used hardened functions such as SPI controller, I²C controller and timer/counter. MachXO2-640/U and higher density devices also provide User Flash Memory (UFM). These hardened functions and the UFM interface to the core logic and routing through a WISHBONE interface. The UFM can also be accessed through the SPI, I²C and JTAG ports.

Every device in the family has a JTAG port that supports programming and configuration of the device as well as access to the user logic. The MachXO2 devices are available for operation from 3.3 V, 2.5 V and 1.2 V power supplies, providing easy integration into the overall system.

PFU Blocks

The core of the MachXO2 device consists of PFU blocks, which can be programmed to perform logic, arithmetic, distributed RAM and distributed ROM functions. Each PFU block consists of four interconnected slices numbered 0 to 3 as shown in Figure 2-3. Each slice contains two LUTs and two registers. There are 53 inputs and 25 outputs associated with each PFU block.

Figure 2-3. PFU Block Diagram



Slices

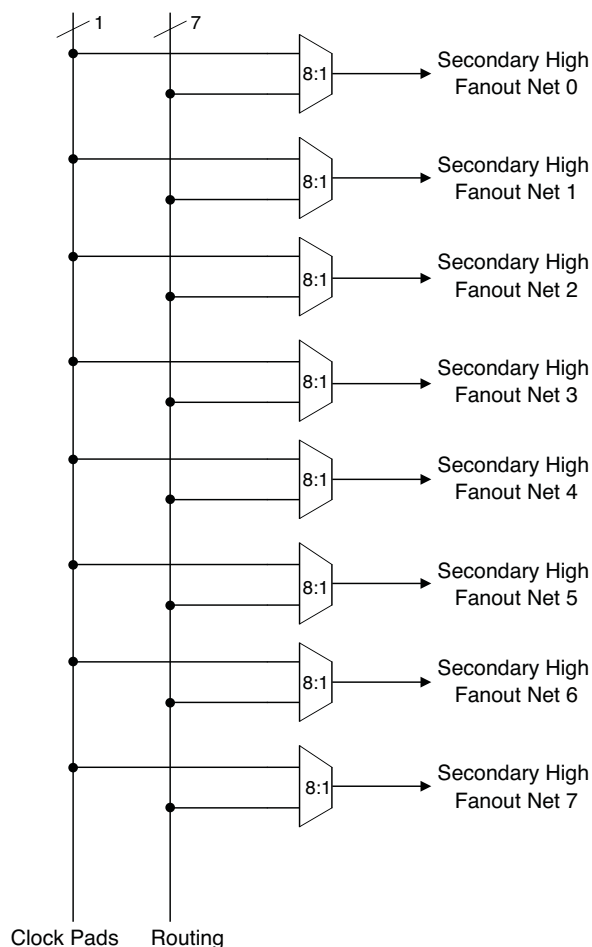
Slices 0-3 contain two LUT4s feeding two registers. Slices 0-2 can be configured as distributed memory. Table 2-1 shows the capability of the slices in PFU blocks along with the operation modes they enable. In addition, each PFU contains logic that allows the LUTs to be combined to perform functions such as LUT5, LUT6, LUT7 and LUT8. The control logic performs set/reset functions (programmable as synchronous/ asynchronous), clock select, chip-select and wider RAM/ROM functions.

Table 2-1. Resources and Modes Available per Slice

Slice	PFU Block	
	Resources	Modes
Slice 0	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 1	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 2	2 LUT4s and 2 Registers	Logic, Ripple, RAM, ROM
Slice 3	2 LUT4s and 2 Registers	Logic, Ripple, ROM

Figure 2-4 shows an overview of the internal logic of the slice. The registers in the slice can be configured for positive/negative and edge triggered or level sensitive clocks. All slices have 15 inputs from routing and one from the carry-chain (from the adjacent slice or PFU). There are seven outputs: six for routing and one to carry-chain (to the adjacent PFU). Table 2-2 lists the signals associated with Slices 0-3.

Figure 2-6. Secondary High Fanout Nets for MachXO2 Devices



sysCLOCK Phase Locked Loops (PLLs)

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The MachXO2-640U, MachXO2-1200/U and larger devices have one or more sysCLOCK PLL. CLKI is the reference frequency input to the PLL and its source can come from an external I/O pin or from internal routing. CLKFB is the feedback signal to the PLL which can come from internal routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The MachXO2 sysCLOCK PLLs support high resolution (16-bit) fractional-N synthesis. Fractional-N frequency synthesis allows the user to generate an output clock which is a non-integer multiple of the input frequency. For more information about using the PLL with Fractional-N synthesis, please see TN1199, [MachXO2 sysCLOCK PLL Design and Usage Guide](#).

Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The output dividers may also be cascaded together to generate low frequency clocks. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the MachXO2 clock distribution network directly or general purpose routing resources can be used.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected. A block diagram of the PLL is shown in Figure 2-7.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock.

Figure 2-8. sysMEM Memory Primitives

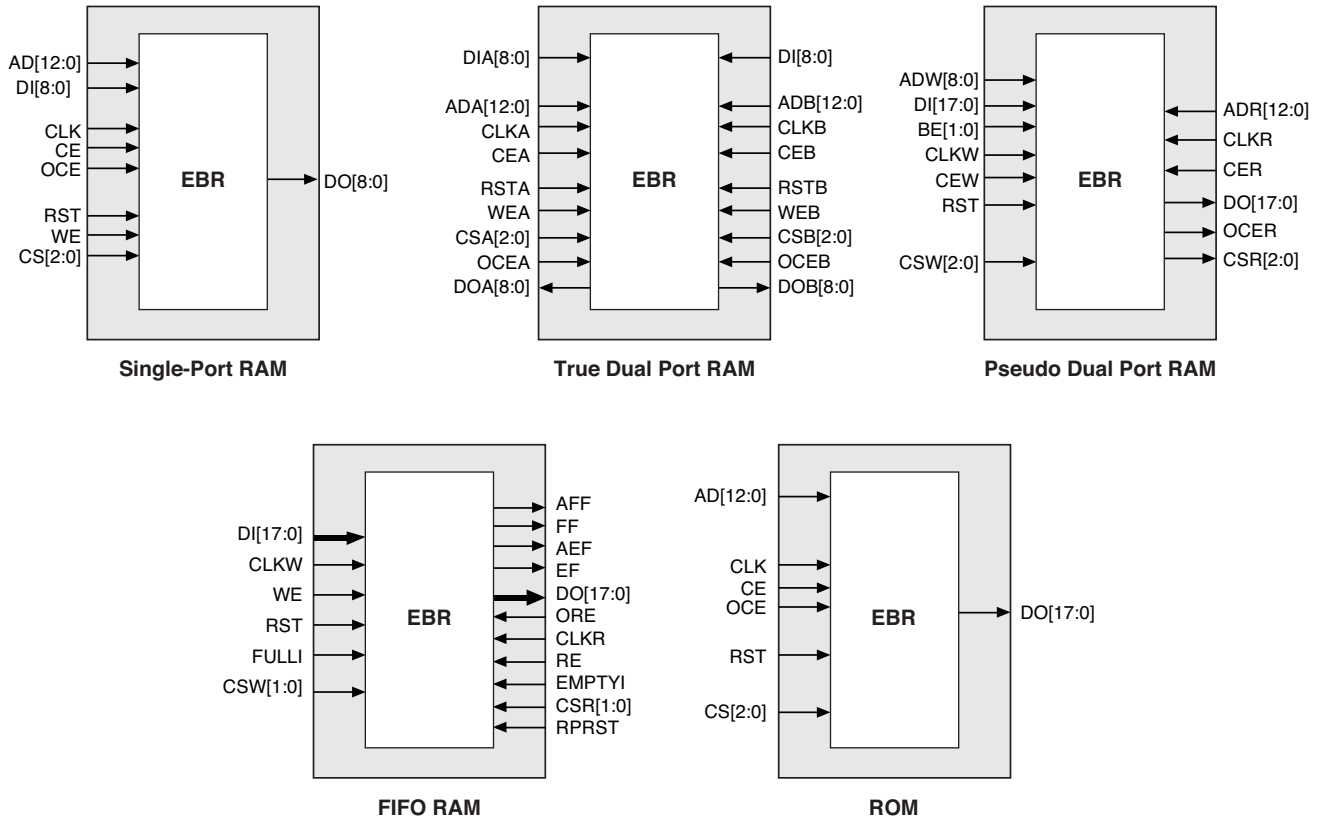


Table 2-6. EBR Signal Descriptions

Port Name	Description	Active State
CLK	Clock	Rising Clock Edge
CE	Clock Enable	Active High
OCE ¹	Output Clock Enable	Active High
RST	Reset	Active High
BE ¹	Byte Enable	Active High
WE	Write Enable	Active High
AD	Address Bus	—
DI	Data In	—
DO	Data Out	—
CS	Chip Select	Active High
AFF	FIFO RAM Almost Full Flag	—
FF	FIFO RAM Full Flag	—
AEF	FIFO RAM Almost Empty Flag	—
EF	FIFO RAM Empty Flag	—
RPRST	FIFO RAM Read Pointer Reset	—

1. Optional signals.

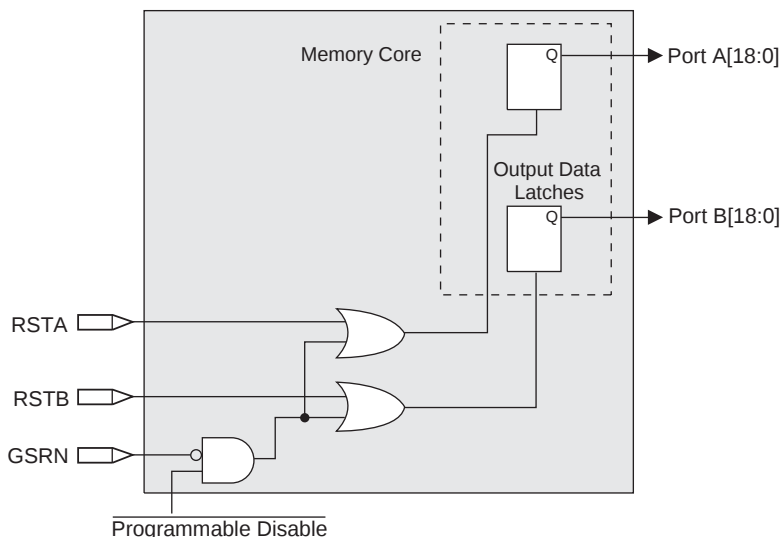
2. For dual port EBR primitives a trailing 'A' or 'B' in the signal name specifies the EBR port A or port B respectively.

3. For FIFO RAM mode primitive, a trailing 'R' or 'W' in the signal name specifies the FIFO read port or write port respectively.

4. For FIFO RAM mode primitive FULLI has the same function as CSW(2) and EMPTYI has the same function as CSR(2).

5. In FIFO mode, CLKW is the write port clock, CSW is the write port chip select, CLKR is the read port clock, CSR is the read port chip select, ORE is the output read enable.

Figure 2-9. Memory Core Reset

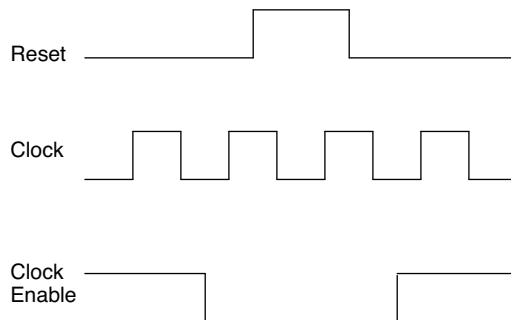


For further information on the sysMEM EBR block, please refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the reset is released, as shown in Figure 2-10. The GSR input to the EBR is always asynchronous.

Figure 2-10. EBR Asynchronous Reset (Including GSR) Timing Diagram



If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of $1/f_{MAX}$ (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

If an EBR is pre-loaded during configuration, the GSR input must be disabled or the release of the GSR during device wake up must occur before the release of the device I/Os becoming active.

These instructions apply to all EBR RAM, ROM and FIFO implementations. For the EBR FIFO mode, the GSR signal is always enabled and the WE and RE signals act like the clock enable signals in Figure 2-10. The reset timing rules apply to the RPRreset input versus the RE input and the RST input versus the WE and RE inputs. Both RST and RPRreset are always asynchronous EBR inputs. For more details refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

Note that there are no reset restrictions if the EBR synchronous reset is used and the EBR GSR input is disabled.

Figure 2-18. MachXO2-1200U, MachXO2-2000/U, MachXO2-4000 and MachXO2-7000 Banks

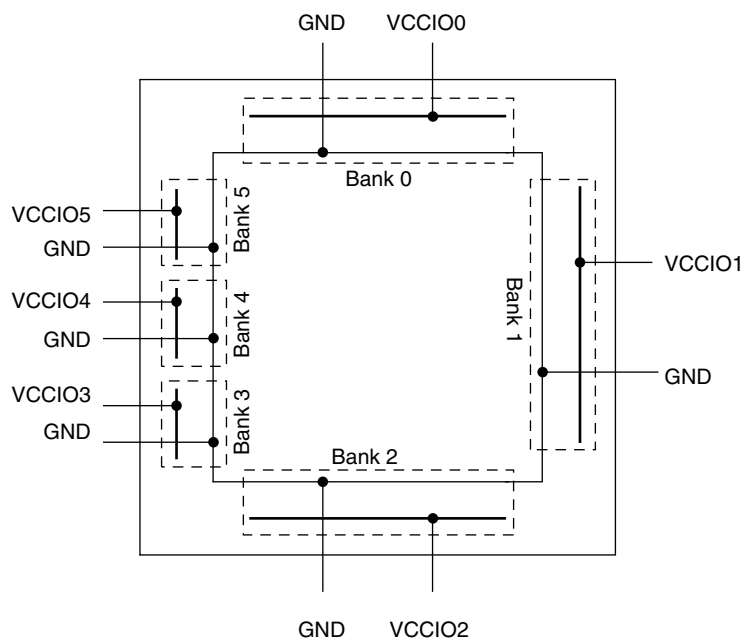
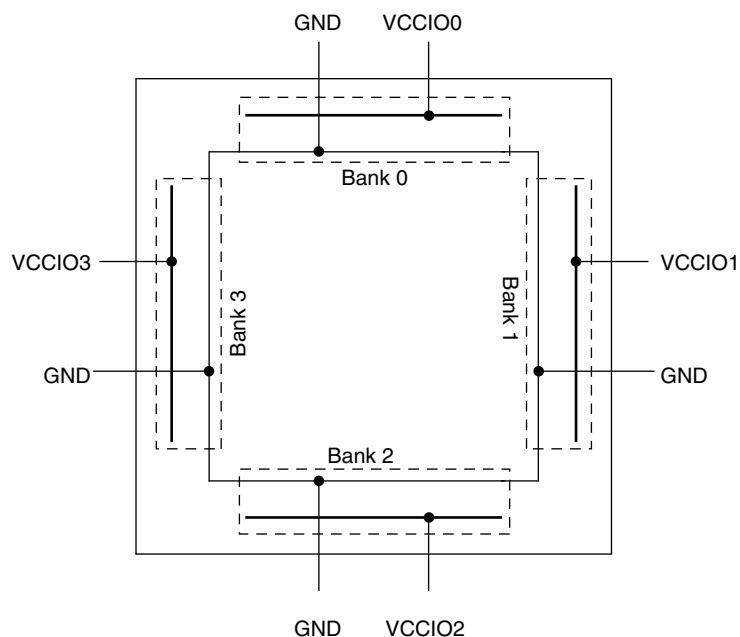


Figure 2-19. MachXO2-256, MachXO2-640/U and MachXO2-1200 Banks



Power-On-Reset Voltage Levels^{1, 2, 3, 4, 5}

Symbol	Parameter	Min.	Typ.	Max.	Units
V_{PORUP}	Power-On-Reset ramp up trip point (band gap based circuit monitoring V_{CCINT} and V_{CCIO0})	0.9	—	1.06	V
$V_{PORUPEXT}$	Power-On-Reset ramp up trip point (band gap based circuit monitoring external V_{CC} power supply)	1.5	—	2.1	V
$V_{PORDNBG}$	Power-On-Reset ramp down trip point (band gap based circuit monitoring V_{CCINT})	0.75	—	0.93	V
$V_{PORDNBGEXT}$	Power-On-Reset ramp down trip point (band gap based circuit monitoring V_{CC})	0.98	—	1.33	V
$V_{PORDNSRAM}$	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V_{CCINT})	—	0.6	—	V
$V_{PORDNSRAMEXT}$	Power-On-Reset ramp down trip point (SRAM based circuit monitoring V_{CC})	—	0.96	—	V

1. These POR trip points are only provided for guidance. Device operation is only characterized for power supply voltages specified under recommended operating conditions.
2. For devices without voltage regulators V_{CCINT} is the same as the V_{CC} supply voltage. For devices with voltage regulators, V_{CCINT} is regulated from the V_{CC} supply voltage.
3. Note that V_{PORUP} (min.) and $V_{PORDNBG}$ (max.) are in different process corners. For any given process corner $V_{PORDNBG}$ (max.) is always 12.0 mV below V_{PORUP} (min.).
4. $V_{PORUPEXT}$ is for HC devices only. In these devices a separate POR circuit monitors the external V_{CC} power supply.
5. V_{CCIO0} does not have a Power-On-Reset ramp down trip point. V_{CCIO0} must remain within the Recommended Operating Conditions to ensure proper operation.

Programming/Erase Specifications

Symbol	Parameter	Min.	Max. ¹	Units
N_{PROG}	Flash Programming cycles per $t_{RETENTION}$	—	10,000	Cycles
	Flash functional programming cycles	—	100,000	
$t_{RETENTION}$	Data retention at 100 °C junction temperature	10	—	Years
	Data retention at 85 °C junction temperature	20	—	

1. Maximum Flash memory reads are limited to 7.5E13 cycles over the lifetime of the product.

Hot Socketing Specifications^{1, 2, 3}

Symbol	Parameter	Condition	Max.	Units
I_{DK}	Input or I/O leakage Current	$0 < V_{IN} < V_{IH}$ (MAX)	+/-1000	μA

1. Insensitive to sequence of V_{CC} and V_{CCIO} . However, assumes monotonic rise/fall rates for V_{CC} and V_{CCIO} .
2. $0 < V_{CC} < V_{CC} (MAX)$, $0 < V_{CCIO} < V_{CCIO} (MAX)$.
3. I_{DK} is additive to I_{PU} , I_{PD} or I_{BH} .

ESD Performance

Please refer to the [MachXO2 Product Family Qualification Summary](#) for complete qualification data, including ESD performance.

LVDS Emulation

MachXO2 devices can support LVDS outputs via emulation (LVDS25E). The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all devices. The scheme shown in Figure 3-1 is one possible solution for LVDS standard implementation. Resistor values in Figure 3-1 are industry standard values for 1% resistors.

Figure 3-1. LVDS Using External Resistors (LVDS25E)

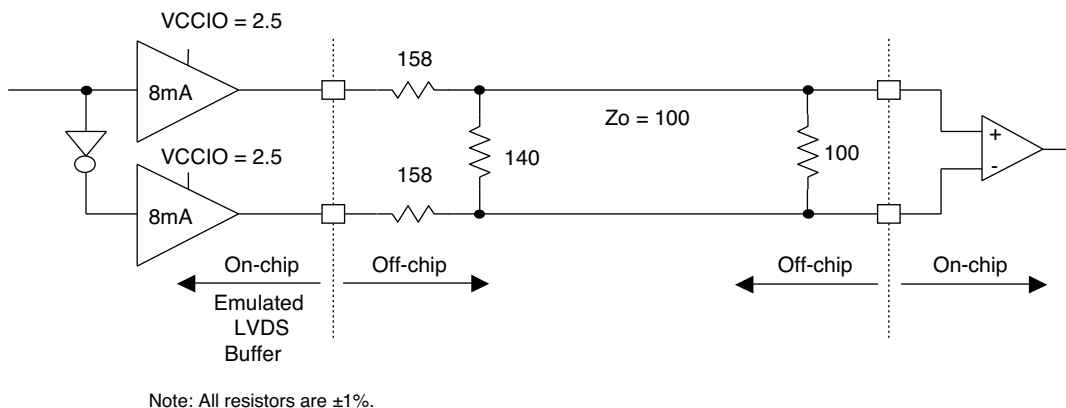


Table 3-1. LVDS25E DC Conditions

Over Recommended Operating Conditions

Parameter	Description	Typ.	Units
Z_{OUT}	Output impedance	20	Ohms
R_S	Driver series resistor	158	Ohms
R_P	Driver parallel resistor	140	Ohms
R_T	Receiver termination	100	Ohms
V_{OH}	Output high voltage	1.43	V
V_{OL}	Output low voltage	1.07	V
V_{OD}	Output differential voltage	0.35	V
V_{CM}	Output common mode voltage	1.25	V
Z_{BACK}	Back impedance	100.5	Ohms
I_{DC}	DC output current	6.03	mA

LVPECL

The MachXO2 family supports the differential LVPECL standard through emulation. This output standard is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all the devices. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Differential LVPECL is one possible solution for point-to-point signals.

Figure 3-3. Differential LVPECL

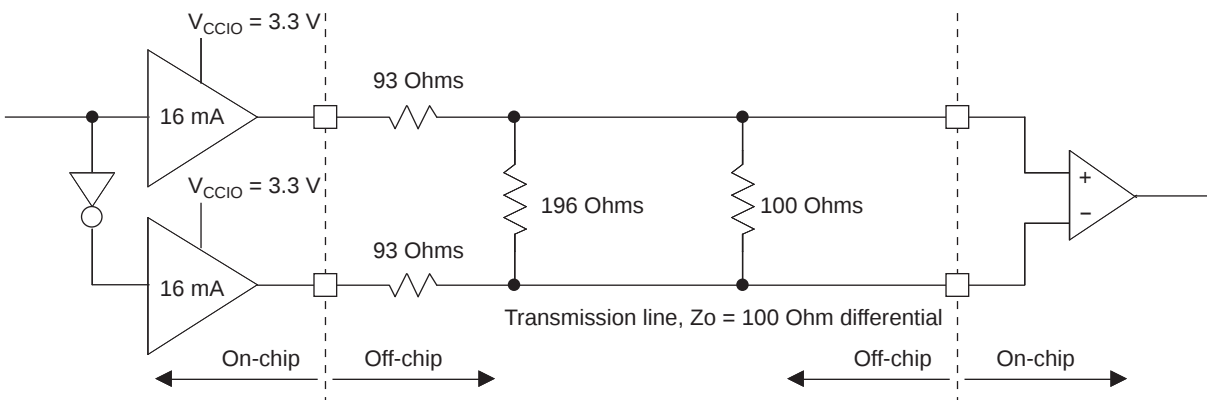


Table 3-3. LVPECL DC Conditions¹

Over Recommended Operating Conditions

Symbol	Description	Nominal	Units
Z_{OUT}	Output impedance	20	Ohms
R_S	Driver series resistor	93	Ohms
R_P	Driver parallel resistor	196	Ohms
R_T	Receiver termination	100	Ohms
V_{OH}	Output high voltage	2.05	V
V_{OL}	Output low voltage	1.25	V
V_{OD}	Output differential voltage	0.80	V
V_{CM}	Output common mode voltage	1.65	V
Z_{BACK}	Back impedance	100.5	Ohms
I_{DC}	DC output current	12.11	mA

1. For input buffer, see LVDS table.

For further information on LVPECL, BLVDS and other differential interfaces please see details of additional technical documentation at the end of the data sheet.

Typical Building Block Function Performance – HC/HE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	-6 Timing	Units
Basic Functions		
16-bit decoder	8.9	ns
4:1 MUX	7.5	ns
16:1 MUX	8.3	ns

Register-to-Register Performance

Function	-6 Timing	Units
Basic Functions		
16:1 MUX	412	MHz
16-bit adder	297	MHz
16-bit counter	324	MHz
64-bit counter	161	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	183	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	500	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{HPLL}	Clock to Data Hold – PIO Input Register	MachXO2-1200HC-HE	0.41	—	0.48	—	0.55	—	ns
		MachXO2-2000HC-HE	0.42	—	0.49	—	0.56	—	ns
		MachXO2-4000HC-HE	0.43	—	0.50	—	0.58	—	ns
		MachXO2-7000HC-HE	0.46	—	0.54	—	0.62	—	ns
t _{SU_DELPLL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200HC-HE	2.88	—	3.19	—	3.72	—	ns
		MachXO2-2000HC-HE	2.87	—	3.18	—	3.70	—	ns
		MachXO2-4000HC-HE	2.96	—	3.28	—	3.81	—	ns
		MachXO2-7000HC-HE	3.05	—	3.35	—	3.87	—	ns
t _{H_DELPLL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200HC-HE	–0.83	—	–0.83	—	–0.83	—	ns
		MachXO2-2000HC-HE	–0.83	—	–0.83	—	–0.83	—	ns
		MachXO2-4000HC-HE	–0.87	—	–0.87	—	–0.87	—	ns
		MachXO2-7000HC-HE	–0.91	—	–0.91	—	–0.91	—	ns
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Aligned ^{9, 12}									
t _{DVA}	Input Data Valid After CLK	All MachXO2 devices, all sides	—	0.317	—	0.344	—	0.368	UI
t _{DVE}	Input Data Hold After CLK		0.742	—	0.702	—	0.668	—	UI
f _{DATA}	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Centered ^{9, 12}									
t _{SU}	Input Data Setup Before CLK	All MachXO2 devices, all sides	0.566	—	0.560	—	0.538	—	ns
t _{HO}	Input Data Hold After CLK		0.778	—	0.879	—	1.090	—	ns
f _{DATA}	DDRX1 Input Data Speed		—	300	—	250	—	208	Mbps
f _{DDRX1}	DDRX1 SCLK Frequency		—	150	—	125	—	104	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Aligned ^{9, 12}									
t _{DVA}	Input Data Valid After CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.316	—	0.342	—	0.364	UI
t _{DVE}	Input Data Hold After CLK		0.710	—	0.675	—	0.679	—	UI
f _{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Centered ^{9, 12}									
t _{SU}	Input Data Setup Before CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	0.233	—	0.219	—	0.198	—	ns
t _{HO}	Input Data Hold After CLK		0.287	—	0.287	—	0.344	—	ns
f _{DATA}	DDRX2 Serial Input Data Speed		—	664	—	554	—	462	Mbps
f _{DDRX2}	DDRX2 ECLK Frequency		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDR4 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR4_RX.ECLK.Aligned ^{9, 12}									
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only. ¹¹	—	0.290	—	0.320	—	0.345	UI
t _{DVE}	Input Data Hold After ECLK		0.739	—	0.699	—	0.703	—	UI
f _{DATA}	DDR4 Serial Input Data Speed		—	756	—	630	—	524	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
Generic DDR4 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR4_RX.ECLK.Centered ^{9, 12}									
t _{SU}	Input Data Setup Before ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only. ¹¹	0.233	—	0.219	—	0.198	—	ns
t _{HO}	Input Data Hold After ECLK		0.287	—	0.287	—	0.344	—	ns
f _{DATA}	DDR4 Serial Input Data Speed		—	756	—	630	—	524	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
7:1 LVDS Inputs (GDDR71_RX.ECLK.7:1) ^{9, 12}									
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only. ¹¹	—	0.290	—	0.320	—	0.345	UI
t _{DVE}	Input Data Hold After ECLK		0.739	—	0.699	—	0.703	—	UI
f _{DATA}	DDR71 Serial Input Data Speed		—	756	—	630	—	524	Mbps
f _{DDR71}	DDR71 ECLK Frequency		—	378	—	315	—	262	MHz
f _{CLKIN}	7:1 Input Clock Frequency (SCLK) (minimum limited by PLL)		—	108	—	90	—	75	MHz
Generic DDR Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_TX.SCLK.Aligned ^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	All MachXO2 devices, all sides.	—	0.520	—	0.550	—	0.580	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.520	—	0.550	—	0.580	ns
f _{DATA}	DDR1 Output Data Speed		—	300	—	250	—	208	Mbps
f _{DDR1}	DDR1 SCLK frequency		—	150	—	125	—	104	MHz
Generic DDR Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_TX.SCLK.Centered ^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	All MachXO2 devices, all sides.	1.210	—	1.510	—	1.870	—	ns
t _{DVA}	Output Data Valid After CLK Output		1.210	—	1.510	—	1.870	—	ns
f _{DATA}	DDR1 Output Data Speed		—	300	—	250	—	208	Mbps
f _{DDR1}	DDR1 SCLK Frequency (minimum limited by PLL)		—	150	—	125	—	104	MHz
Generic DDRX2 Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_TX.ECLK.Aligned ^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.200	—	0.215	—	0.230	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.200	—	0.215	—	0.230	ns
f _{DATA}	DDR2 Serial Output Data Speed		—	664	—	554	—	462	Mbps
f _{DDR2}	DDR2 ECLK frequency		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
LPDDR ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.369	—	0.395	—	0.421	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.529	—	0.530	—	0.527	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM LPDDR Serial Data Speed		—	280	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency		—	140	—	125	—	104	MHz
f _{LPDDR}	LPDDR Data Transfer Rate		0	280	0	250	0	208	Mbps
DDR ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.350	—	0.387	—	0.414	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.545	—	0.538	—	0.532	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	300	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency		—	150	—	125	—	104	MHz
f _{MEM_DDR}	MEM DDR Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps
DDR2 ^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.360	—	0.378	—	0.406	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.555	—	0.549	—	0.542	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	300	—	250	—	208	Mbps
f _{SCLK}	SCLK Frequency		—	150	—	125	—	104	MHz
f _{MEM_DDR2}	MEM DDR2 Data Transfer Rate		N/A	300	N/A	250	N/A	208	Mbps

- Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
- General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0pf load, fast slew rate.
- Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
- DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.
- 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
- For Generic DDRX1 mode $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$.
- The t_{SU_DEL} and t_{H_DEL} values use the SCLK_ZERHOLD default step size. Each step is 105 ps (-6), 113 ps (-5), 120 ps (-4).
- This number for general purpose usage. Duty cycle tolerance is +/- 10%.
- Duty cycle is +/-5% for system usage.
- The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
- High-speed DDR and LVDS not supported in SG32 (32 QFN) packages.
- Advance information for MachXO2 devices in 48 QFN packages.
- DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{SU_DEL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-256ZE	2.62	—	2.91	—	3.14	—	ns
		MachXO2-640ZE	2.56	—	2.85	—	3.08	—	ns
		MachXO2-1200ZE	2.30	—	2.57	—	2.79	—	ns
		MachXO2-2000ZE	2.25	—	2.50	—	2.70	—	ns
		MachXO2-4000ZE	2.39	—	2.60	—	2.76	—	ns
		MachXO2-7000ZE	2.17	—	2.33	—	2.43	—	ns
t _{H_DEL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-256ZE	–0.44	—	–0.44	—	–0.44	—	ns
		MachXO2-640ZE	–0.43	—	–0.43	—	–0.43	—	ns
		MachXO2-1200ZE	–0.28	—	–0.28	—	–0.28	—	ns
		MachXO2-2000ZE	–0.31	—	–0.31	—	–0.31	—	ns
		MachXO2-4000ZE	–0.34	—	–0.34	—	–0.34	—	ns
		MachXO2-7000ZE	–0.21	—	–0.21	—	–0.21	—	ns
f _{MAX_IO}	Clock Frequency of I/O and PFU Register	All MachXO2 devices	—	150	—	125	—	104	MHz
General I/O Pin Parameters (Using Edge Clock without PLL)									
t _{COE}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-2000ZE	—	11.10	—	11.51	—	11.91	ns
		MachXO2-4000ZE	—	10.89	—	11.28	—	11.67	ns
		MachXO2-7000ZE	—	11.10	—	11.51	—	11.91	ns
t _{SUE}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	–0.23	—	–0.23	—	–0.23	—	ns
		MachXO2-2000ZE	–0.23	—	–0.23	—	–0.23	—	ns
		MachXO2-4000ZE	–0.15	—	–0.15	—	–0.15	—	ns
		MachXO2-7000ZE	–0.23	—	–0.23	—	–0.23	—	ns
t _{HE}	Clock to Data Hold – PIO Input Register	MachXO2-1200ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-2000ZE	3.81	—	4.11	—	4.52	—	ns
		MachXO2-4000ZE	3.60	—	3.89	—	4.28	—	ns
		MachXO2-7000ZE	3.81	—	4.11	—	4.52	—	ns
t _{SU_DELE}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-2000ZE	2.78	—	3.11	—	3.40	—	ns
		MachXO2-4000ZE	3.11	—	3.48	—	3.79	—	ns
		MachXO2-7000ZE	2.94	—	3.30	—	3.60	—	ns
t _{H_DELE}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200ZE	–0.29	—	–0.29	—	–0.29	—	ns
		MachXO2-2000ZE	–0.29	—	–0.29	—	–0.29	—	ns
		MachXO2-4000ZE	–0.46	—	–0.46	—	–0.46	—	ns
		MachXO2-7000ZE	–0.37	—	–0.37	—	–0.37	—	ns
General I/O Pin Parameters (Using Primary Clock with PLL)									
t _{COPLL}	Clock to Output – PIO Output Register	MachXO2-1200ZE	—	7.95	—	8.07	—	8.19	ns
		MachXO2-2000ZE	—	7.97	—	8.10	—	8.22	ns
		MachXO2-4000ZE	—	7.98	—	8.10	—	8.23	ns
		MachXO2-7000ZE	—	8.02	—	8.14	—	8.26	ns
t _{SUPLL}	Clock to Data Setup – PIO Input Register	MachXO2-1200ZE	0.85	—	0.85	—	0.89	—	ns
		MachXO2-2000ZE	0.84	—	0.84	—	0.86	—	ns
		MachXO2-4000ZE	0.84	—	0.84	—	0.85	—	ns
		MachXO2-7000ZE	0.83	—	0.83	—	0.81	—	ns

Figure 3-5. Receiver RX.CLK.Aligned and MEM DDR Input Waveforms

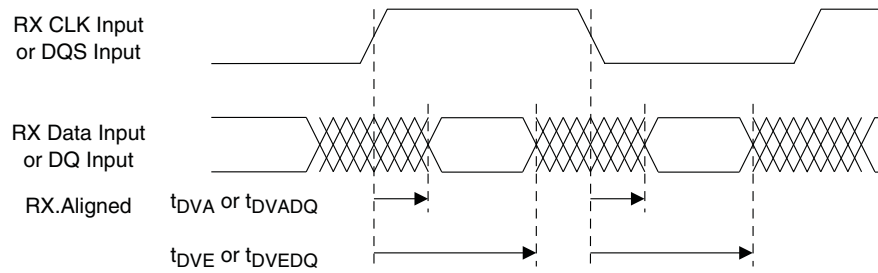


Figure 3-6. Receiver RX.CLK.Centered Waveforms

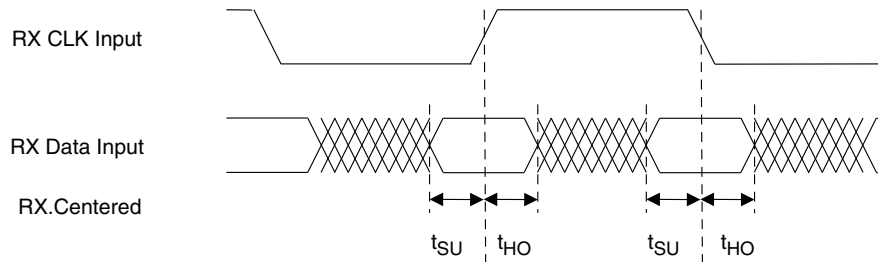


Figure 3-7. Transmitter TX.CLK.Aligned Waveforms

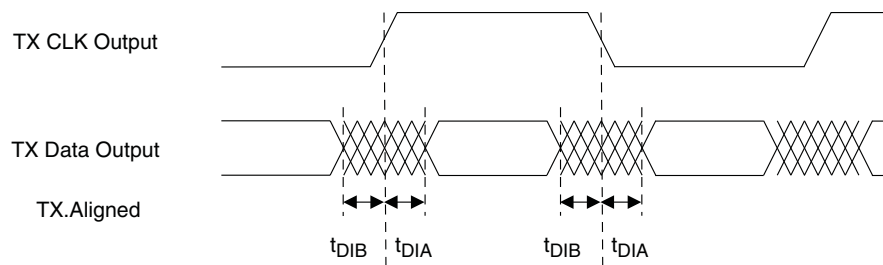
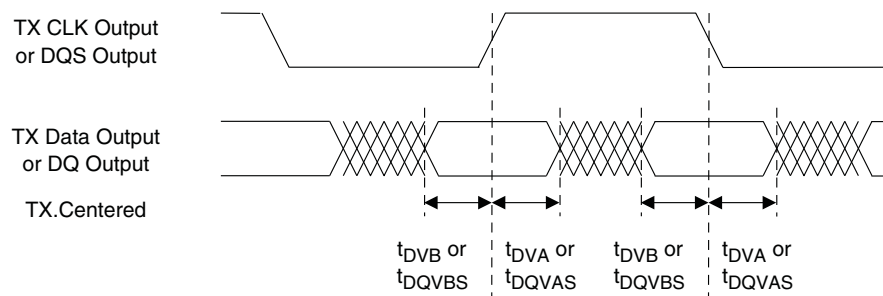


Figure 3-8. Transmitter TX.CLK.Centered and MEM DDR Output Waveforms



I²C Port Timing Specifications^{1, 2}

Symbol	Parameter	Min.	Max.	Units
f _{MAX}	Maximum SCL clock frequency	—	400	kHz

- MachXO2 supports the following modes:
 - Standard-mode (Sm), with a bit rate up to 100 kbit/s (user and configuration mode)
 - Fast-mode (Fm), with a bit rate up to 400 kbit/s (user and configuration mode)
- Refer to the I²C specification for timing requirements.

SPI Port Timing Specifications¹

Symbol	Parameter	Min.	Max.	Units
f _{MAX}	Maximum SCK clock frequency	—	45	MHz

- Applies to user mode only. For configuration mode timing specifications, refer to sysCONFIG Port Timing Specifications table in this data sheet.

Switching Test Conditions

Figure 3-13 shows the output test load used for AC testing. The specific values for resistance, capacitance, voltage, and other test conditions are shown in Table 3-5.

Figure 3-13. Output Test Load, LVTTTL and LVCMOS Standards

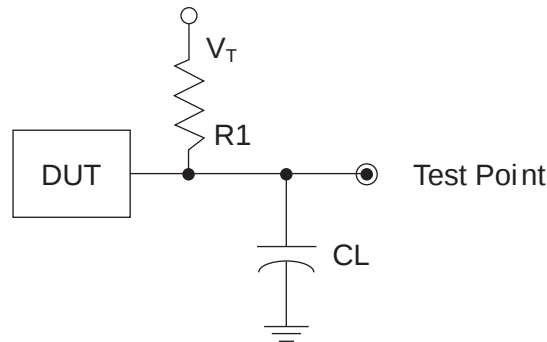


Table 3-5. Test Fixture Required Components, Non-Terminated Interfaces

Test Condition	R1	CL	Timing Ref.	VT
LVTTTL and LVCMOS settings (L -> H, H -> L)	∞	0pF	LVTTTL, LVCMOS 3.3 = 1.5 V	—
			LVCMOS 2.5 = V _{CCIO} /2	—
			LVCMOS 1.8 = V _{CCIO} /2	—
			LVCMOS 1.5 = V _{CCIO} /2	—
			LVCMOS 1.2 = V _{CCIO} /2	—
LVTTTL and LVCMOS 3.3 (Z -> H)	188	0pF	1.5 V	V _{OL}
LVTTTL and LVCMOS 3.3 (Z -> L)			1.5 V	V _{OH}
Other LVCMOS (Z -> H)			V _{CCIO} /2	V _{OL}
Other LVCMOS (Z -> L)			V _{CCIO} /2	V _{OH}
LVTTTL + LVCMOS (H -> Z)			V _{OH} - 0.15 V	V _{OL}
LVTTTL + LVCMOS (L -> Z)			V _{OL} - 0.15 V	V _{OH}

Note: Output test conditions for all other interfaces are determined by the respective standards.

	MachXO2-2000						MachXO2-2000U
	49 WLCSP	100 TQFP	132 csBGA	144 TQFP	256 caBGA	256 ftBGA	484 ftBGA
General Purpose I/O per Bank							
Bank 0	19	18	25	27	50	50	70
Bank 1	0	21	26	28	52	52	68
Bank 2	13	20	28	28	52	52	72
Bank 3	0	6	7	8	16	16	24
Bank 4	0	6	8	10	16	16	16
Bank 5	6	8	10	10	20	20	28
Total General Purpose Single-Ended I/O	38	79	104	111	206	206	278
Differential I/O per Bank							
Bank 0	7	9	13	14	25	25	35
Bank 1	0	10	13	14	26	26	34
Bank 2	6	10	14	14	26	26	36
Bank 3	0	3	3	4	8	8	12
Bank 4	0	3	4	5	8	8	8
Bank 5	3	4	5	5	10	10	14
Total General Purpose Differential I/O	16	39	52	56	103	103	139
Dual Function I/O							
	24	31	33	33	33	33	37
High-speed Differential I/O							
Bank 0	5	4	8	9	14	14	18
Gearboxes							
Number of 7:1 or 8:1 Output Gearbox Available (Bank 0)	5	4	8	9	14	14	18
Number of 7:1 or 8:1 Input Gearbox Available (Bank 2)	6	10	14	14	14	14	18
DQS Groups							
Bank 1	0	1	2	2	2	2	2
VCCIO Pins							
Bank 0	2	2	3	3	4	4	10
Bank 1	0	2	3	3	4	4	10
Bank 2	1	2	3	3	4	4	10
Bank 3	0	1	1	1	1	1	3
Bank 4	0	1	1	1	2	2	4
Bank 5	1	1	1	1	1	1	3
VCC	2	2	4	4	8	8	12
GND	4	8	10	12	24	24	48
NC	0	1	1	4	1	1	105
Reserved for Configuration	1	1	1	1	v	1	1
Total Count of Bonded Pins	39	100	132	144	256	256	484

High-Performance Commercial Grade Devices without Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HE-4TG100C	2112	1.2 V	–4	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-5TG100C	2112	1.2 V	–5	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-6TG100C	2112	1.2 V	–6	Halogen-Free TQFP	100	COM
LCMXO2-2000HE-4TG144C	2112	1.2 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-5TG144C	2112	1.2 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-6TG144C	2112	1.2 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-2000HE-4MG132C	2112	1.2 V	–4	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-5MG132C	2112	1.2 V	–5	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-6MG132C	2112	1.2 V	–6	Halogen-Free csBGA	132	COM
LCMXO2-2000HE-4BG256C	2112	1.2 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-5BG256C	2112	1.2 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-6BG256C	2112	1.2 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-2000HE-4FTG256C	2112	1.2 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-2000HE-5FTG256C	2112	1.2 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-2000HE-6FTG256C	2112	1.2 V	–6	Halogen-Free ftBGA	256	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHE-4FG484C	2112	1.2 V	–4	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHE-5FG484C	2112	1.2 V	–5	Halogen-Free fpBGA	484	COM
LCMXO2-2000UHE-6FG484C	2112	1.2 V	–6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-4000HE-4TG144C	4320	1.2 V	–4	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-5TG144C	4320	1.2 V	–5	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-6TG144C	4320	1.2 V	–6	Halogen-Free TQFP	144	COM
LCMXO2-4000HE-4MG132C	4320	1.2 V	–4	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-5MG132C	4320	1.2 V	–5	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-6MG132C	4320	1.2 V	–6	Halogen-Free csBGA	132	COM
LCMXO2-4000HE-4BG256C	4320	1.2 V	–4	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-4MG184C	4320	1.2 V	–4	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-5MG184C	4320	1.2 V	–5	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-6MG184C	4320	1.2 V	–6	Halogen-Free csBGA	184	COM
LCMXO2-4000HE-5BG256C	4320	1.2 V	–5	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-6BG256C	4320	1.2 V	–6	Halogen-Free caBGA	256	COM
LCMXO2-4000HE-4FTG256C	4320	1.2 V	–4	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-5FTG256C	4320	1.2 V	–5	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-6FTG256C	4320	1.2 V	–6	Halogen-Free ftBGA	256	COM
LCMXO2-4000HE-4BG332C	4320	1.2 V	–4	Halogen-Free caBGA	332	COM
LCMXO2-4000HE-5BG332C	4320	1.2 V	–5	Halogen-Free caBGA	332	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4SG32I	1280	2.5 V / 3.3 V	–4	Halogen-Free QFN	32	IND
LCMXO2-1200HC-5SG32I	1280	2.5 V / 3.3 V	–5	Halogen-Free QFN	32	IND
LCMXO2-1200HC-6SG32I	1280	2.5 V / 3.3 V	–6	Halogen-Free QFN	32	IND
LCMXO2-1200HC-4TG100I	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-5TG100I	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-6TG100I	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-1200HC-4MG132I	1280	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-5MG132I	1280	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-6MG132I	1280	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-1200HC-4TG144I	1280	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-5TG144I	1280	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-1200HC-6TG144I	1280	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200UHC-4FTG256I	1280	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-5FTG256I	1280	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-1200UHC-6FTG256I	1280	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HC-4TG100I	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-5TG100I	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-6TG100I	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	100	IND
LCMXO2-2000HC-4MG132I	2112	2.5 V / 3.3 V	–4	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-5MG132I	2112	2.5 V / 3.3 V	–5	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-6MG132I	2112	2.5 V / 3.3 V	–6	Halogen-Free csBGA	132	IND
LCMXO2-2000HC-4TG144I	2112	2.5 V / 3.3 V	–4	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-5TG144I	2112	2.5 V / 3.3 V	–5	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-6TG144I	2112	2.5 V / 3.3 V	–6	Halogen-Free TQFP	144	IND
LCMXO2-2000HC-4BG256I	2112	2.5 V / 3.3 V	–4	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-5BG256I	2112	2.5 V / 3.3 V	–5	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-6BG256I	2112	2.5 V / 3.3 V	–6	Halogen-Free caBGA	256	IND
LCMXO2-2000HC-4FTG256I	2112	2.5 V / 3.3 V	–4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-5FTG256I	2112	2.5 V / 3.3 V	–5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HC-6FTG256I	2112	2.5 V / 3.3 V	–6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHC-4FG484I	2112	2.5 V / 3.3 V	–4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-5FG484I	2112	2.5 V / 3.3 V	–5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHC-6FG484I	2112	2.5 V / 3.3 V	–6	Halogen-Free fpBGA	484	IND

Date	Version	Section	Change Summary
January 2013	02.0	Introduction	Updated the total number IOs to include JTAGENB.
		Architecture	Supported Output Standards table – Added 3.3 V _{CCIO} (Typ.) to LVDS row.
			Changed SRAM CRC Error Detection to Soft Error Detection.
		DC and Switching Characteristics	Power Supply Ramp Rates table – Updated Units column for t _{RAMP} symbol.
			Added new Maximum sysIO Buffer Performance table.
			sysCLOCK PLL Timing table – Updated Min. column values for f _{IN} , f _{OUT} , f _{OUT2} and f _{PFD} parameters. Added t _{SPO} parameter. Updated footnote 6.
			MachXO2 Oscillator Output Frequency table – Updated symbol name for t _{STABLEOSC} .
			DC Electrical Characteristics table – Updated conditions for I _{IL} , I _{IH} symbols.
			Corrected parameters tDQVBS and tDQVAS
			Corrected MachXO2 ZE parameters tDVADQ and tDVEDQ
		Pinout Information	Included the MachXO2-4000HE 184 csBGA package.
		Ordering Information	Updated part number.
April 2012	01.9	Architecture	Removed references to TN1200.
		Ordering Information	Updated the Device Status portion of the MachXO2 Part Number Description to include the 50 parts per reel for the WLCSP package.
			Added new part number and footnote 2 for LCMXO2-1200ZE-1UWG25ITR50.
			Updated footnote 1 for LCMXO2-1200ZE-1UWG25ITR.
		Supplemental Information	Removed references to TN1200.
March 2012	01.8	Introduction	Added 32 QFN packaging information to Features bullets and MachXO2 Family Selection Guide table.
		DC and Switching Characteristics	Changed 'STANDBY' to 'USERSTDBY' in Standby Mode timing diagram.
		Pinout Information	Removed footnote from Pin Information Summary tables.
			Added 32 QFN package to Pin Information Summary table.
		Ordering Information	Updated Part Number Description and Ordering Information tables for 32 QFN package.
			Updated topside mark diagram in the Ordering Information section.